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PTO/SB/08A (08-00)

Substitution for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		<i>Complete if Known</i>	
		Application Number	09/844,669
		Filing Date	April 30, 2001
		First Named Inventor	THEKKATH
		Group Art Unit	2113
		Examiner Name	McCarthy, Christopher S.
Sheet	1 of 1	Attorney Docket Number	MTEC-003/00US

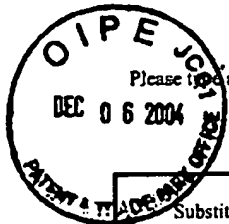
OTHER – NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T ²
CM	D1	F. Chow et al., "Engineering a RISC Compiler System," <i>IEEE COMP-CON</i> , March 1986, pp. 132-137.		
	D2	Susan J. EGGERS, et al., "Techniques for Efficient Inline Tracing on a Shared-Memory Multiprocessor," University of Washington, <i>1990 ACM</i> , pp. 37-47.		
	D3	M.D. Smith, "Tracing with Pixie," <i>Technical Report CSL-TR-91-497</i> , Stanford University, Computer Systems Laboratory, November 1991, pp. 1-29.		
	D4	ATOM Reference Manual, <i>Digital Equipment Corporation</i> , Massachusetts, December 1993, pp. 1-32.		
	D5	A. Srivastava et al., "ATOM: A System for Building Customized Program Analysis Tools," <i>WRL Research Report 94/2</i> , Digital Equipment Corporation, Massachusetts, March 1994, pp. 1-23.		
	D6	ATOM User Manual, Digital Equipment Corporation, March 1994, pp. 1-28.		
	D7	B. Cmelik et al., "Shade: A Fast Instruction-Set Simulator for Execution Profiling," <i>Proceedings of the 1994 ACM SIGMETRICS Conference</i> , SIGMETRICS, California, May 1994, pp. 128-137.		
	D8	Richard A. UHLIG, et al., "Trace-Driven Memory Simulation: A Survey," Intel Microcomputer Research Lab; University of Michigan, <i>ACM Computing Surveys</i> , Vol. 29, No. 2, June 1997, pp. 128-170.		
	D9	Eric ROTENBERG, et al., "Trace Processors," University of Wisconsin, 1997 <i>IEEE Service Center</i> , 12 pp.		
	D10	E.N. ELNOZAHY, "Address Trace Compression Through Loop Detection and Reduction," <i>©1999 ACM 1-58113-083</i> , pp. 214, 215.		
	D11	Darren JONES, "Opal Coprocessor Interface," <i>MIP Proprietary/Confidential</i> , June 4, 1999, pp. 1-18.		
	D12	Darren JONES, <i>MIPS64™ 5K™ Processor Cores User's Manual</i> , Rev. 1.0, July 4, 1999, pp. 6-1 to 6-26.		
	D13	<i>MIPS64™ 5K™ Processor Cores User's Manual</i> , Rev. 1.0.1., 1999, pp. 247-276.		
	D14	MIPS Technologies; "MIPS64 5K™ Processor Core Integrator's Guide;" [Document No. MD00056]; <i>MIPS Technologies, Inc.</i> ; Rev. 1.2; August 11, 2000; pp. I-II, 1-82.		
	D15	MIPS Technologies; "MIPS64™ 5K™ Processor Core Family Integrator's Guide;" [Document No. MD00106]; <i>©1999-2001 MIPS Technologies, Inc.</i> ; Rev. 02.00; January 15, 2001; pp. I-VIII, 1-75.		
CM	D16	MIPS Technologies; "Core Processor Interface Specification;" [Document No. MD00068]; <i>MIPS Technologies, Inc.</i> ; Rev. 1.11; March 30, 2001; pp. 1-26.		

Examiner Signature	/Christopher McCarthy/	Date Considered	05/01/2006
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PTO/SB/08A (08-00)

Substitute for form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known			
		Application Number	09/844,669		
		Filing Date	April 30, 2001		
		First Named Inventor	THEKKATH		
		Group Art Unit	2113		
		Examiner Name	McCarthy, Christopher S.		
Sheet	1	of	1	Attorney Docket Number	MTEC-003/00US

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CM	1	Embedded Trace Macrocell Specification, Rev. 0/0a, ARM IHI 0014C, ARM Ltd. (1999)	

Examiner Signature	/Christopher Mccarthy/	Date Considered	05/01/2006
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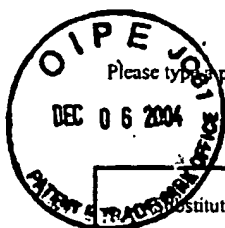
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Sheet	1	of	2

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U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		
CM	P1	3,473,154		Coulour et al.	10/14/1969
	P2	3,585,599		Hitt	06/15/1971
	P3	3,681,534		Burian et al.	08/01/1972
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	P5	3,704,363		Salmassy et al.	11/28/1972
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	P10	4,205,370		Hirtle	05/27/1980
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	P12	4,423,508		Shiozaki et al.	12/27/1983
	P13	4,462,077		York	07/24/1984
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	P42	6,256,777		Ackerman	07/03/2001
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² See attached Kinds of U.S. Patent Documents.

CM	P45	6,467,083		Yamashita	10/15/2002
	P46	6,487,715		Chamdani et al.	11/26/2002
	P47	6,530,076		Ryan et al.	03/04/2003
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	P52	2002/0147965		Swaine et al.	10/10/2002

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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Office ¹	Number ²	Kind Code ³ (if known)		
CM	F1	GB	2 329 048		ARM Limited	10/03/1999
CM	F2	GB	2 329 049		ARM Limited	10/03/1999

Examiner Signature	/Christopher Mccarthy/	Date Considered	05/01/2006
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